

FORM PTO-1449
(REV. 7-80)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
501082.04 (98-0616.03)

APPLICATION NO.
09/652,993

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)
Vishnu K. Agarwal







FILING DATE
August 31, 2000

GROUP ART UNIT
2815



~~U.S. PATENT~~ DOCUMENT

[illegible]

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|--|----|-----------------|---|--------------------|---|---|-------------|----|
| | | | | | | | YES | NO |
|  | AE | 355011329 A | 01/26/80 | JP (Abstract only) |  | | X | |
| | AF | 410070091 A | 03/10/98 | JP (Abstract only) |  | | X | |
| | | |  | |  |  | | |

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|--|----|--|
|  | AG | Anonymous, "Oxide-Free Dielectric/GaAs Interface With No Excess As", IBM Technical Disclosure Bulletin, Vol. 33, No. 11, April 1, 1991, p. 352. |
|  | AH | Schulz, S.E. et al., "Influence of Water Preclean Before Selective Tungsten CVD on Surface Properties of Interconnect and Intermetal Dielectric Materials", Physica Status Solidi A, Vol. 145, No. 2, October 16, 1994, pp. 311-318. |

EXAMINER

DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

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| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----------------|----------|------------------|-------|----------|-------------------------------|
| AA | 3,649,886 | 03/72 | Kooi | 257 | 638 | |
| AB | 4,717,602 | 01/05/88 | Yamazaki | 427 | 583 | |
| AC | 5,232,871 | 08/03/93 | Ho | 438 | 653 | |
| AD | 5,733,816 | 03/31/98 | Iyer et al. | 438 | 592 | |
| AE | 6,153,519 | 11/28/00 | Jain et al. | 438 | 681 | |
| AF | 6,204,203 | 03/20/01 | Narwankar et al. | 438 | 785 | |
| AG | 6,245,662 | 06/12/01 | Naik et al. | 438 | 622 | |
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|----------------------|----|-----------------|----------|---------------|-------|----------|-------------------------------|
| DD | AA | 6,255,688 B1 | 07/03/01 | Lee et al. | 257 | 311 | |
| DD | AB | 6,281,542 B1 | 08/28/01 | Wu | 257 | 308 | |
| DD | AC | 6,320,213 B1 | 11/20/01 | Kirlin et al. | 257 | 295 | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
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| | AL | | | | | | | |
| | AM | | | | | | | |
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